

## DK-107173-UL

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) OR SCHEME

## **CB TEST CERTIFICATE**

**Product** 

Intel® NUC (computer)

Name and address of the applicant

INTEL CORPORATION 2200 MISSION COLLEGE BLVD SANTA CLARA, CA

95054-1537 USA

Name and address of the manufacturer

INTEL CORPORATION 2200 MISSION COLLEGE BLVD SANTA CLARA, CA

95054-1537 USA

Name and address of the factory

GOLDEN ELITE TECHNOLOGY (SHEN ZHEN) LTD

1 NAN HUAN RD SHAJING BAO AN SHENZHEN GUANGDONG 518104

CHINA

Note: When more than one factory, please report on page 2

Additional Information on page 2

Ratings and principal characteristics

19 Vdc, 4.74 A or 19 Vdc, 6.32 A

Trademark / Brand (if any)



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

xNUC11xPAKx, xNUC11xPAHx, xNUC11xPAQx (where x can be a combination of alphanumeric characters, none or blank)

Additional information (if necessary may also be reported on page 2)

Additionally evaluated to EN 62368-1:2014/A11:2017 National Difference specified in the CB Test Report

Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 62368-1:2014

As shown in the Test Report Ref. No. which forms part of this Certificate

ATTCB109126 issued on 2020-12-07

This CB Test Certificate is issued by the National Certification Body



UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA

UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK

UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN

UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2020-12-14 Signature:

Jan-Erik Storgaard